

PVTSizing: A TuRBO-RL-Based Batch-Sampling Optimization Framework for PVT-Robust Analog Circuit Synthesis

Zichen Kong¹, Xiyuan Tang^{1*}, Wei Shi², Yiheng Du¹, Yibo Lin¹, Yuan Wang^{1*}

¹Peking University

²The University of Texas at Austin



*Corresponding authors

Outline

Background & Introduction

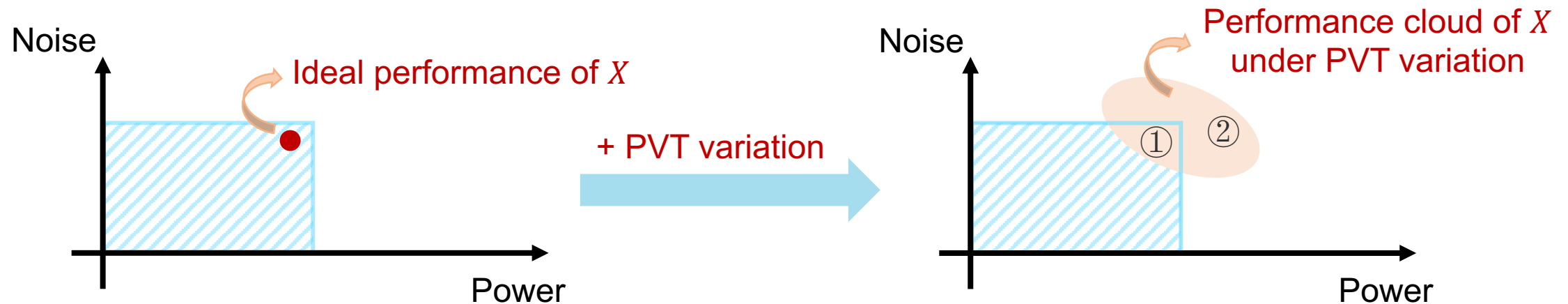
Proposed PVT Sizing

Experimental Results

Conclusion

PVT robustness is significant for analog synthesis.

$X = (W_1, L_1, \dots)$ is a certain set of design solution of analog synthesis.



Performance space that meets given specifications

- ① X **meets** given specifications under some PVT corners.
- ② X **fails to meet** given specifications under some other PVT corners.

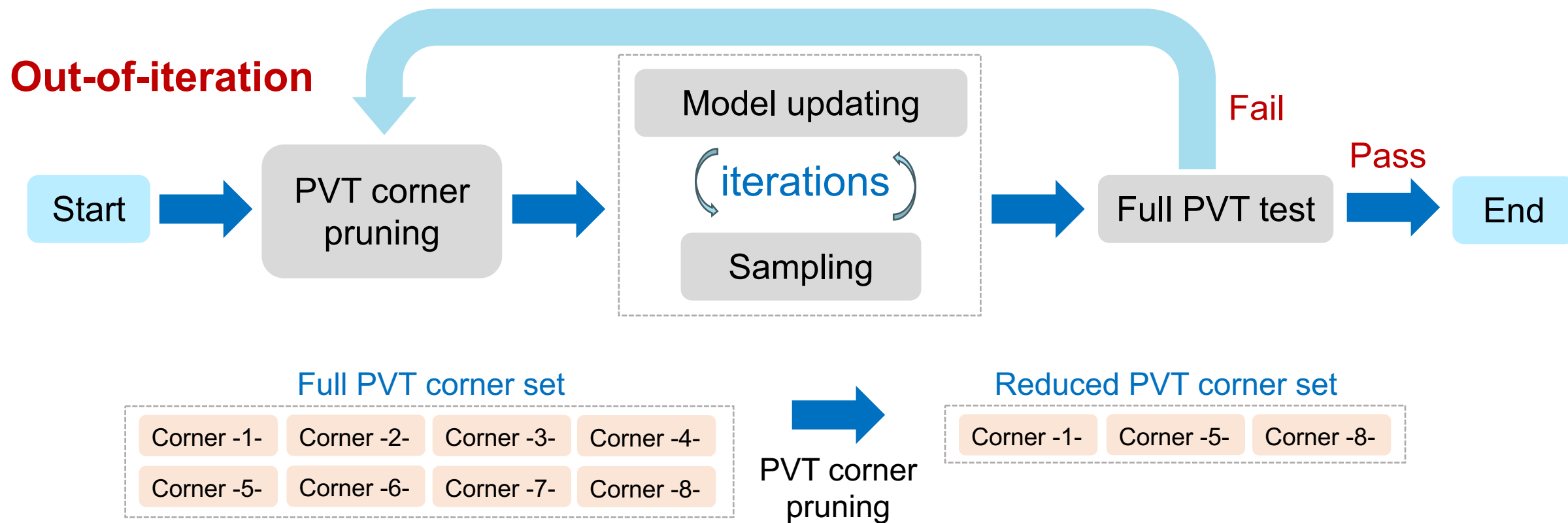
Challenge of PVT-robust analog synthesis

Challenge 1: Randomness of starting point limits success rate.

- The mapping between device sizes and circuit performance is highly nonlinear.
- With bad starting point, it's easy to stuck at the local optimum for a long time.

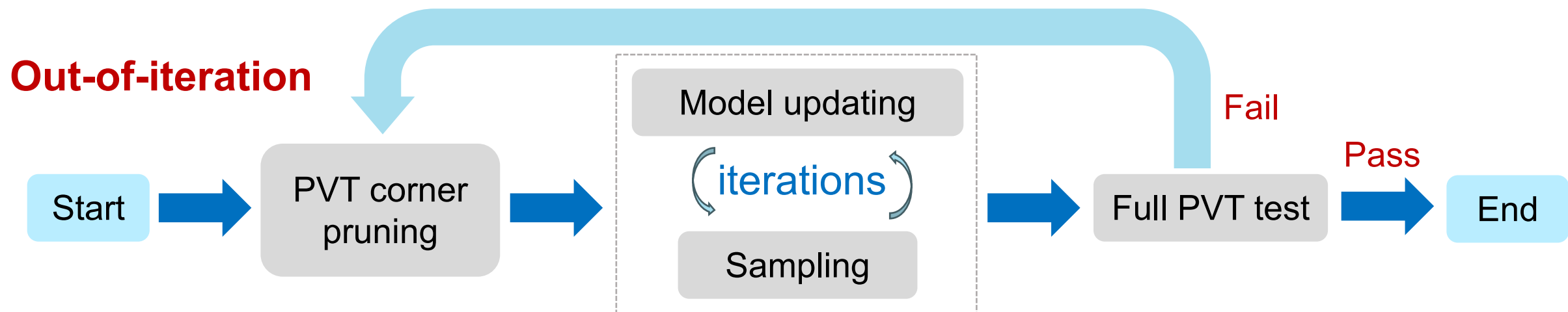
Challenge of PVT-robust analog synthesis

Challenge 2: Out-of-iteration PVT corner pruning leads to corner-overfitting.

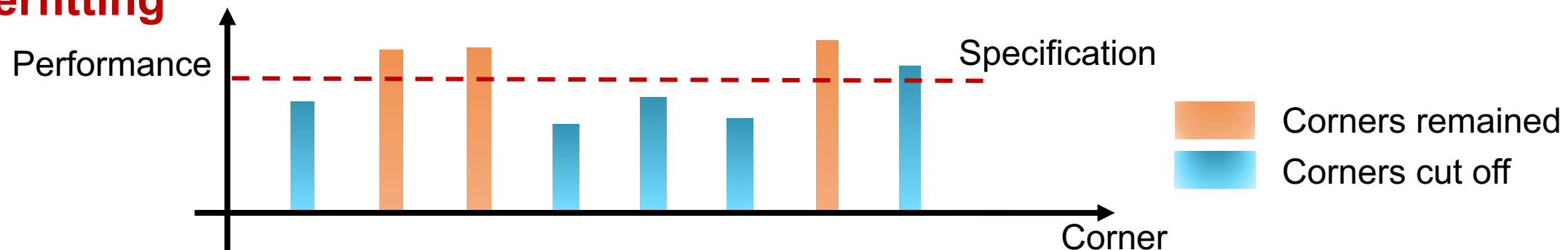


Challenge of PVT-robust analog synthesis

Challenge 2: Out-of-iteration PVT corner pruning leads to corner-overfitting.

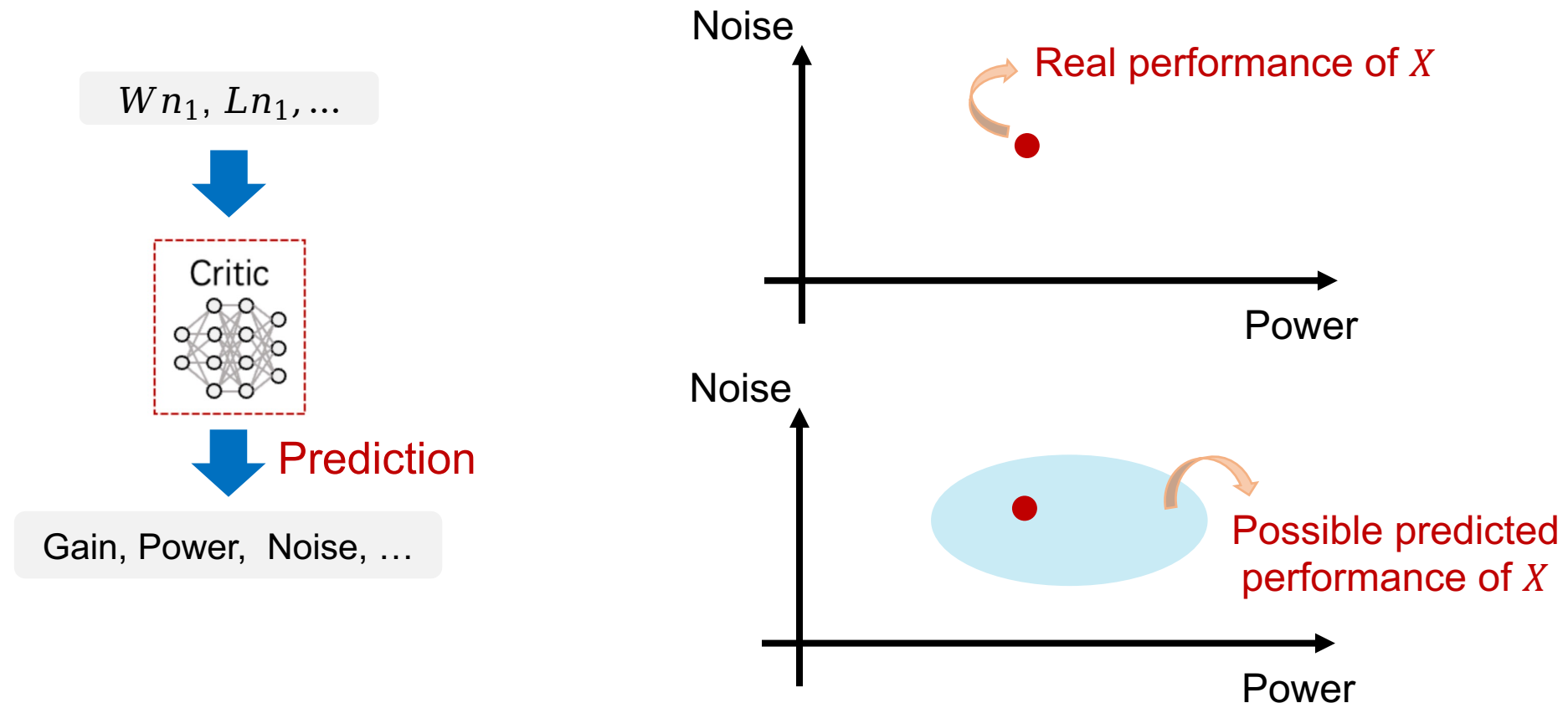


Corner-overfitting



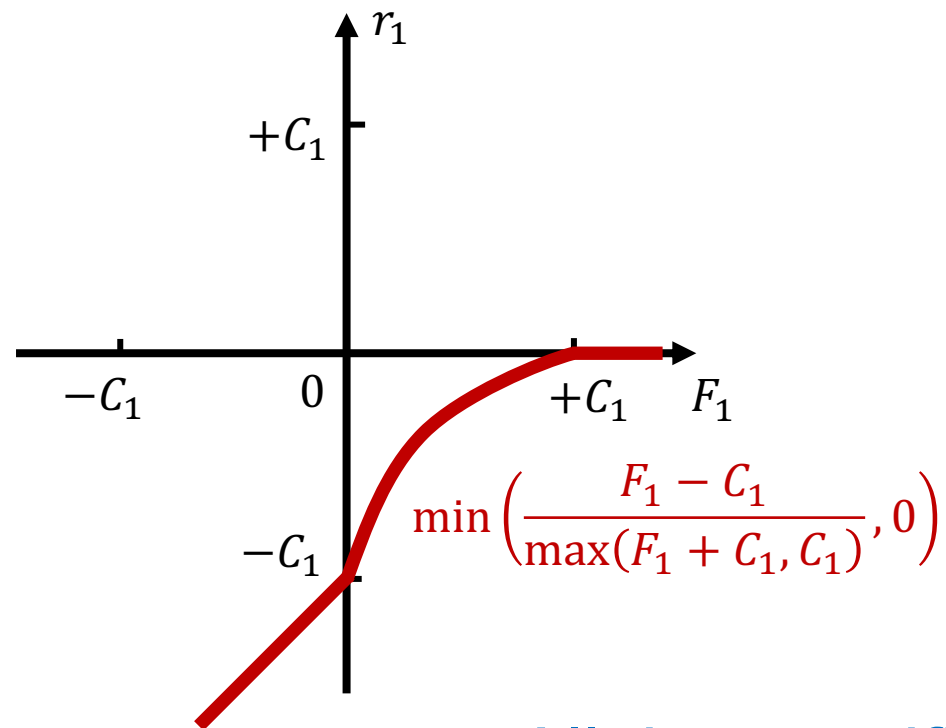
Challenge of PVT-robust analog synthesis

Challenge 3: Inaccurate prediction limits the effectiveness of sample pruning.



Formulation of PVT-robust analog synthesis

Define figure of merit (FoM) to convert multiple specifications into a single target.

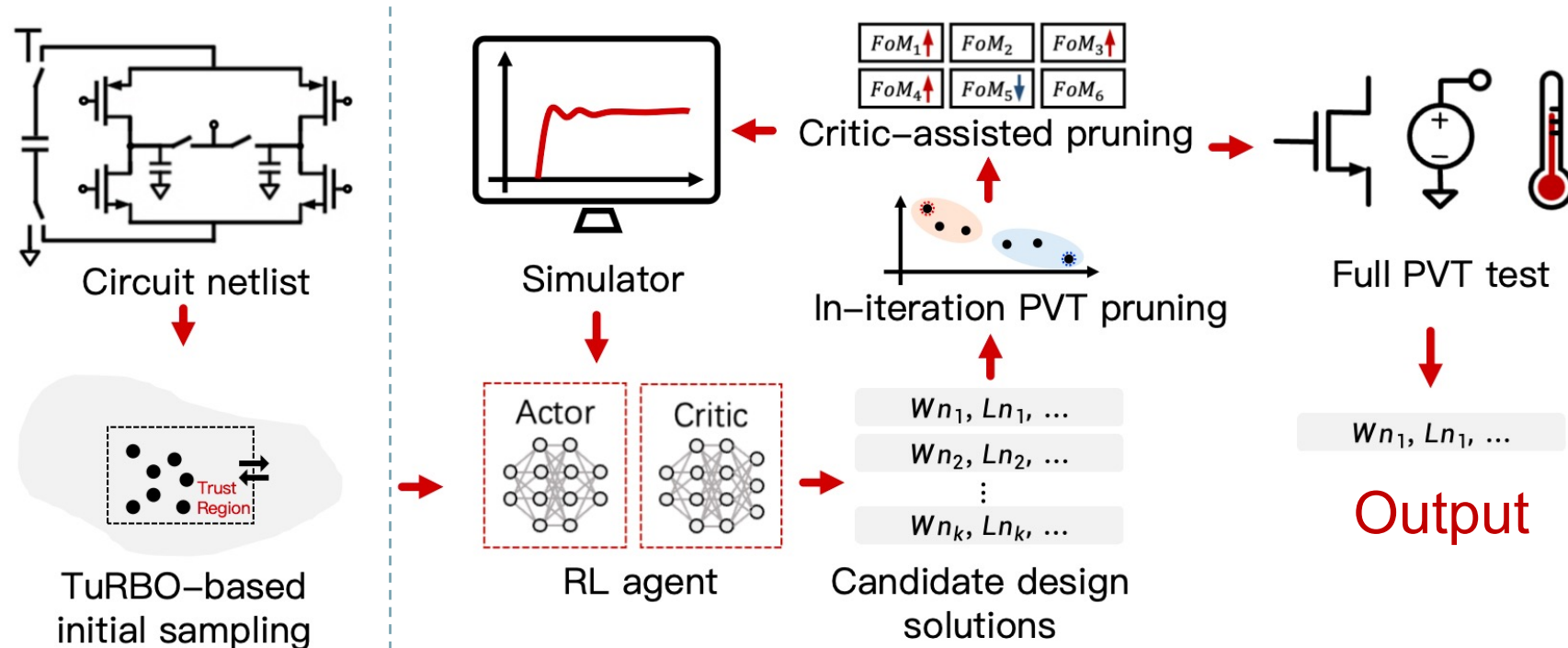


$$FoM = \begin{cases} r, & r < 0 \\ 0.2, & r \geq 0 \end{cases}$$

$$r = \begin{cases} \sum_{i=1}^m \min\left(\frac{\text{Performance } F_i - \text{Specification } C_i}{\max(F_i + C_i, C_i)}, 0\right), & \text{if we want } F_i \geq C_i \\ \sum_{i=1}^m \min\left(\frac{C_i - F_i}{\max(F_i + C_i, C_i)}, 0\right), & \text{if we want } F_i \leq C_i \end{cases}$$

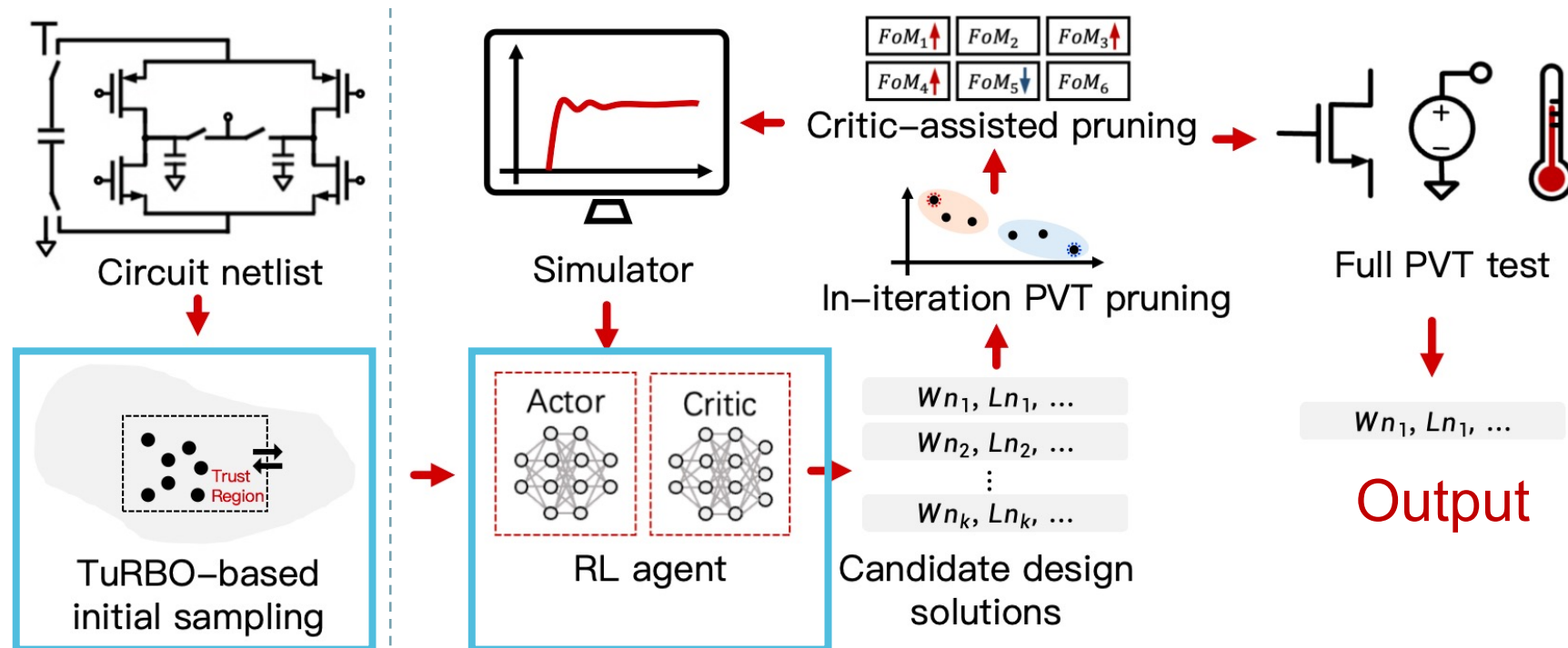
All the specifications are met when $FoM \geq 0$.

This work: PVTsizing



Overview of PVTsizing

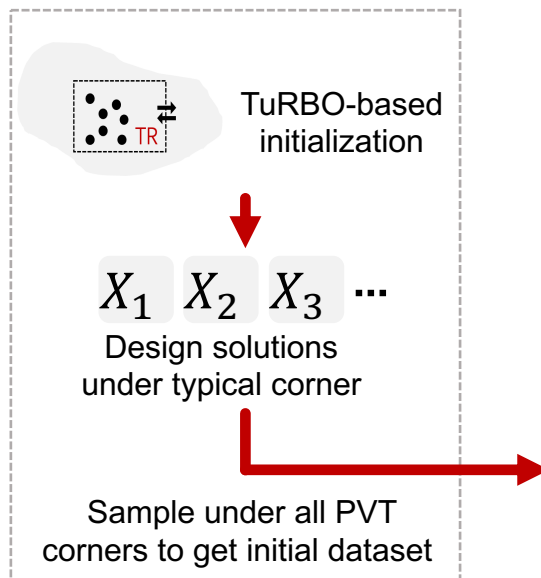
This work: PVTsizing



Contribution 1/3: Divide sizing problem into 1) single-corner initial sampling phase and 2) multi-corner sizing phase to improve success rate.

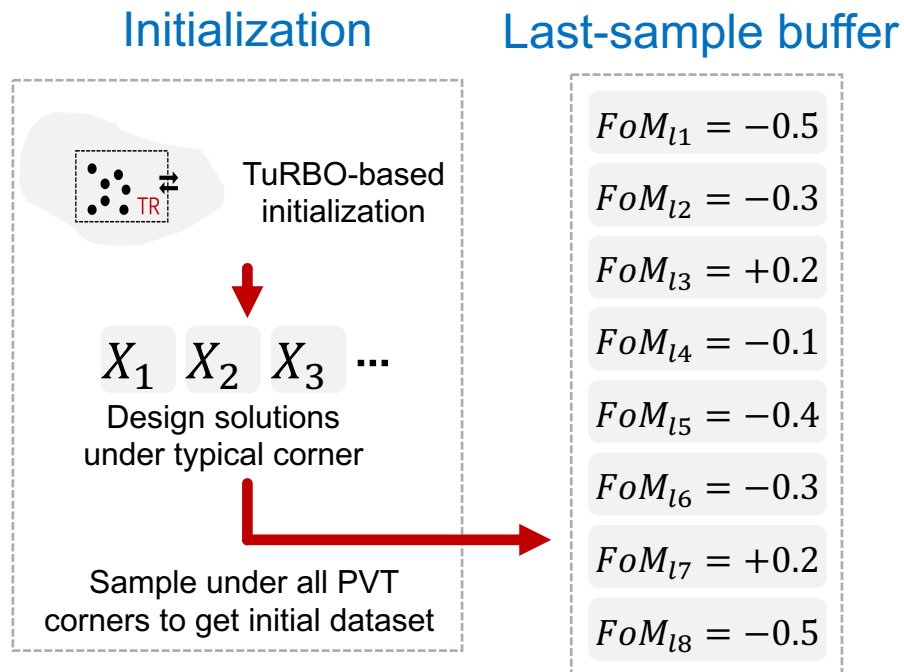
Contribution 1: TuRBO-RL-based optimization framework

Initialization



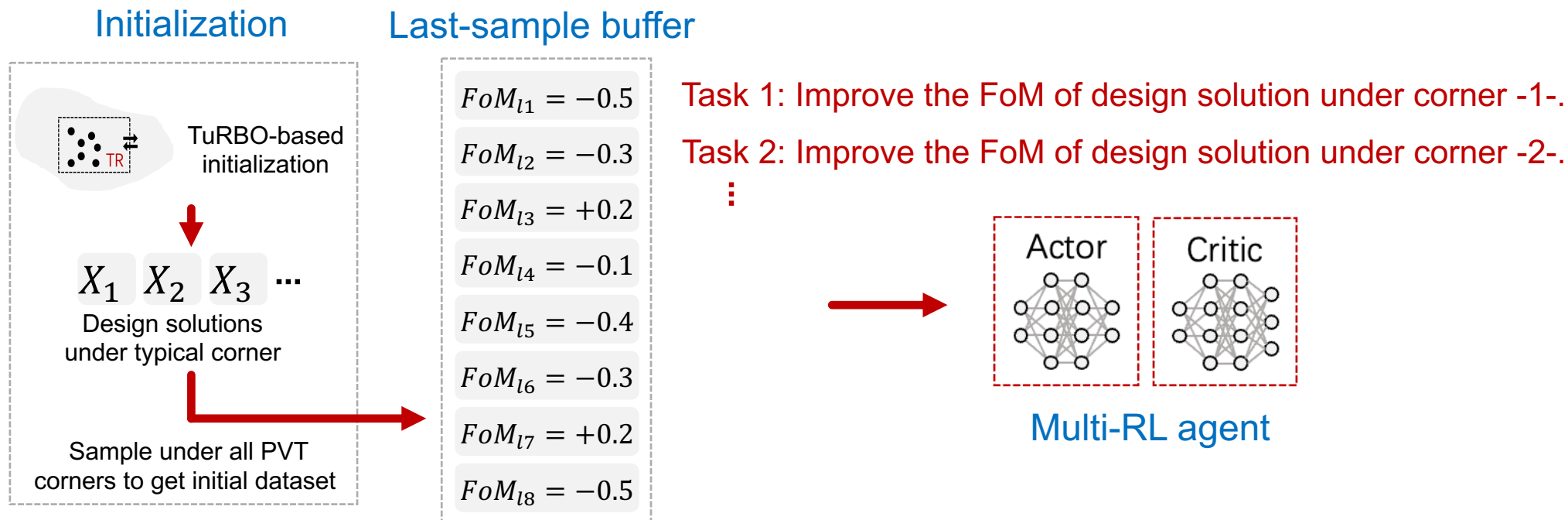
Do TuRBO-based initial sampling.

Contribution 1: TuRBO-RL-based optimization framework



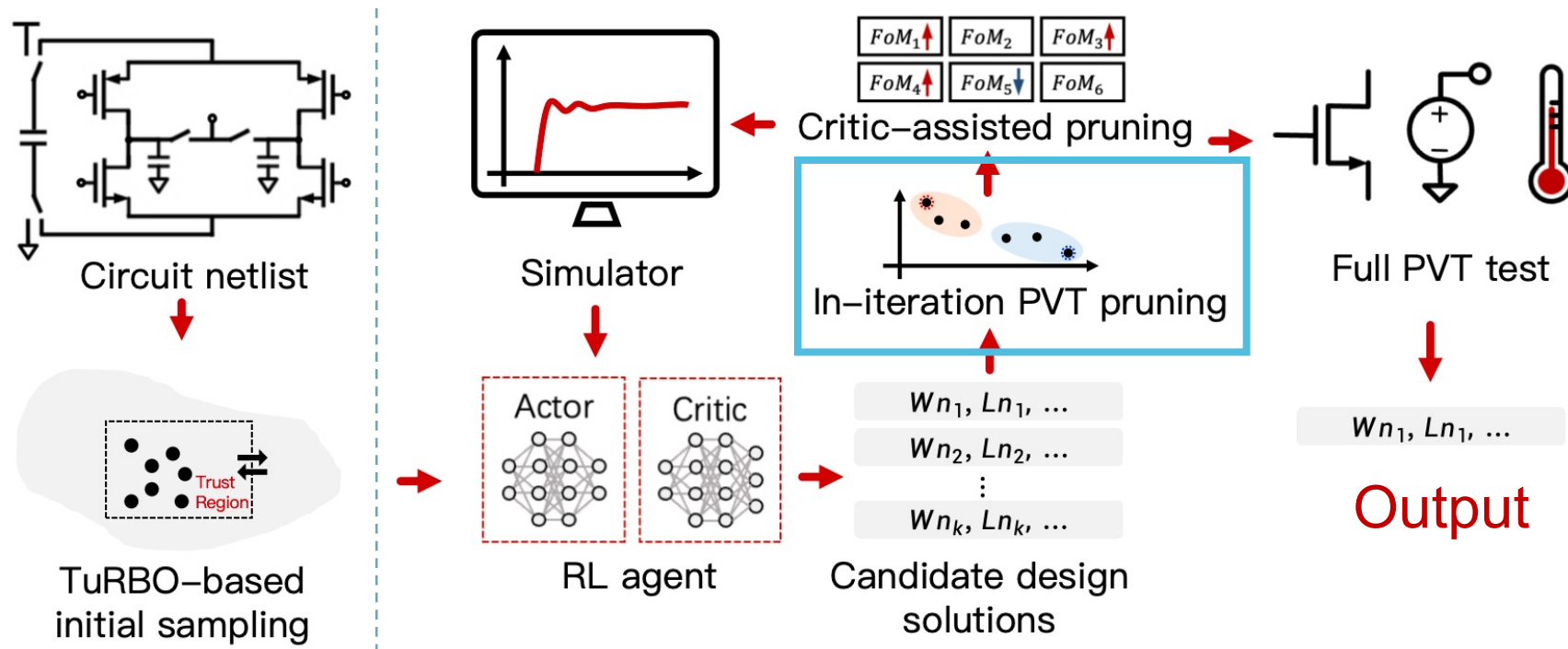
Build last-sample buffer to record the results of latest sampling of each PVT corner.

Contribution 1: TuRBO-RL-based optimization framework



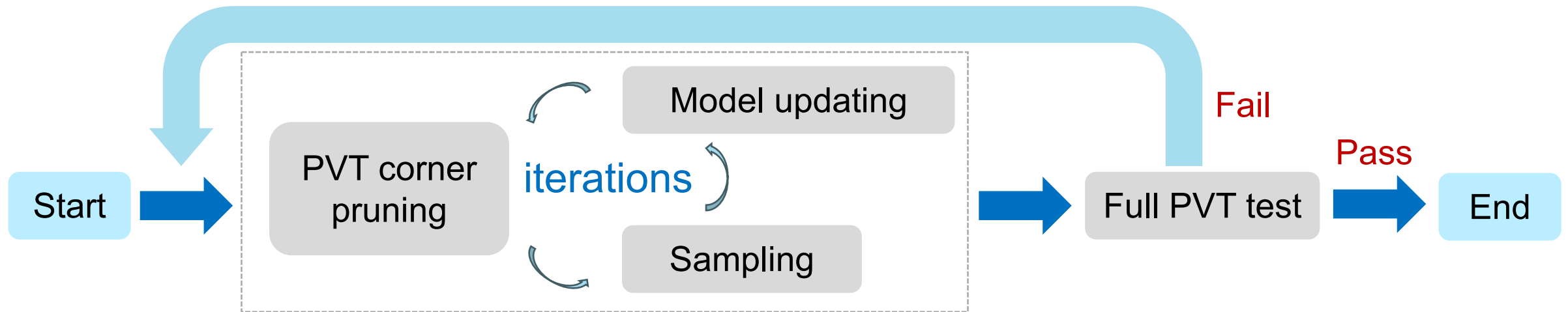
Multi-task reinforcement learning for multi-corner sizing.

This work: PVTsizing

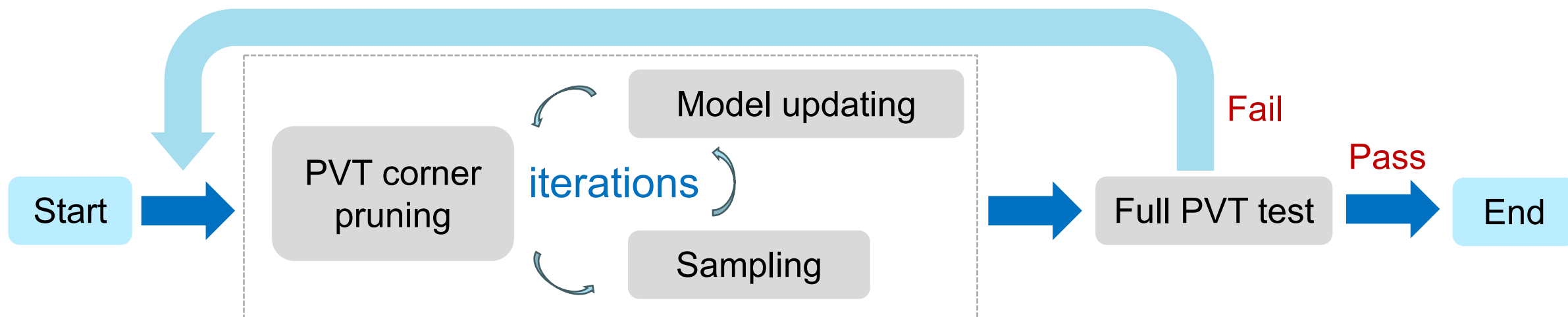


Contribution 2/3: In-iteration PVT pruning based on last-sample buffer

Contribution 2: In-iteration PVT pruning



Contribution 2: In-iteration PVT pruning



Last-sample buffer

$FoM_{l1} = -0.5$	$FoM_{l5} = -0.4$
$FoM_{l2} = -0.3$	$FoM_{l6} = -0.3$
$FoM_{l3} = +0.2$	$FoM_{l7} = +0.2$
$FoM_{l4} = -0.1$	$FoM_{l8} = -0.5$

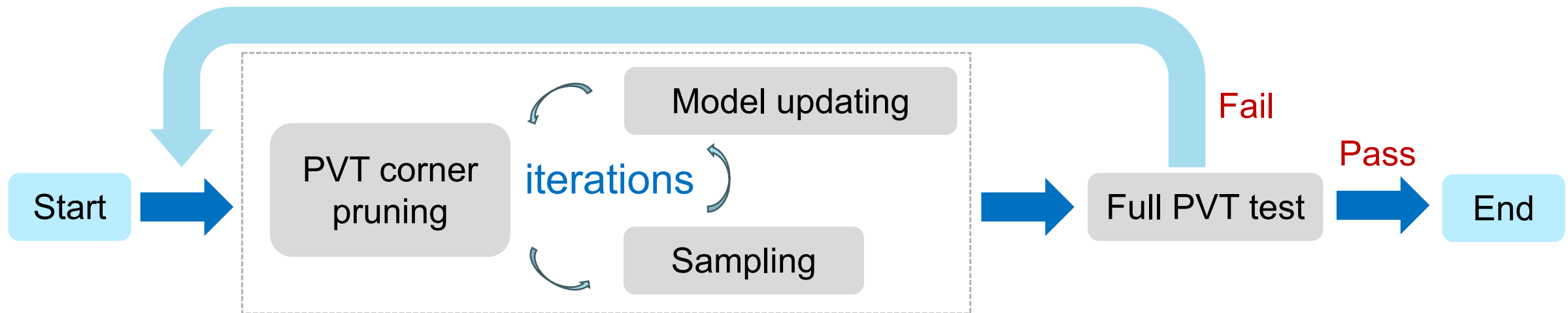
PVT corner
pruning
K-means

$FoM_{l1} = -0.1$	$FoM_{l5} = -0.4$
$FoM_{l2} = -0.3$	$FoM_{l6} = -0.3$
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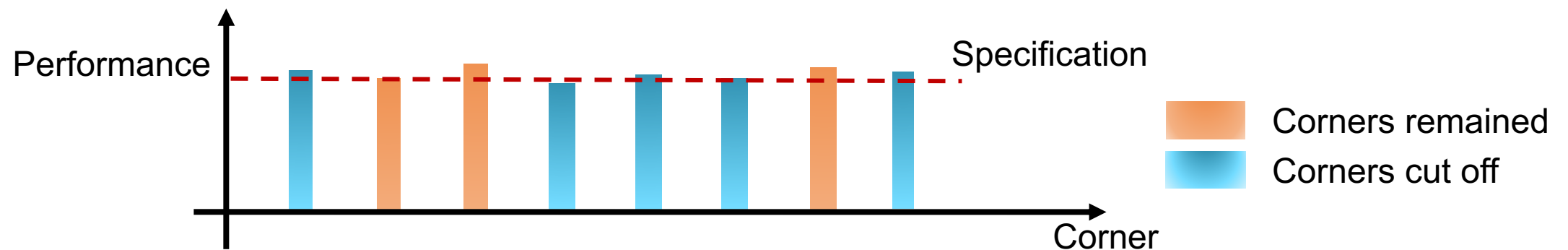
Reduced PVT corner set

Corner -1-	Corner -5-	Corner -8-
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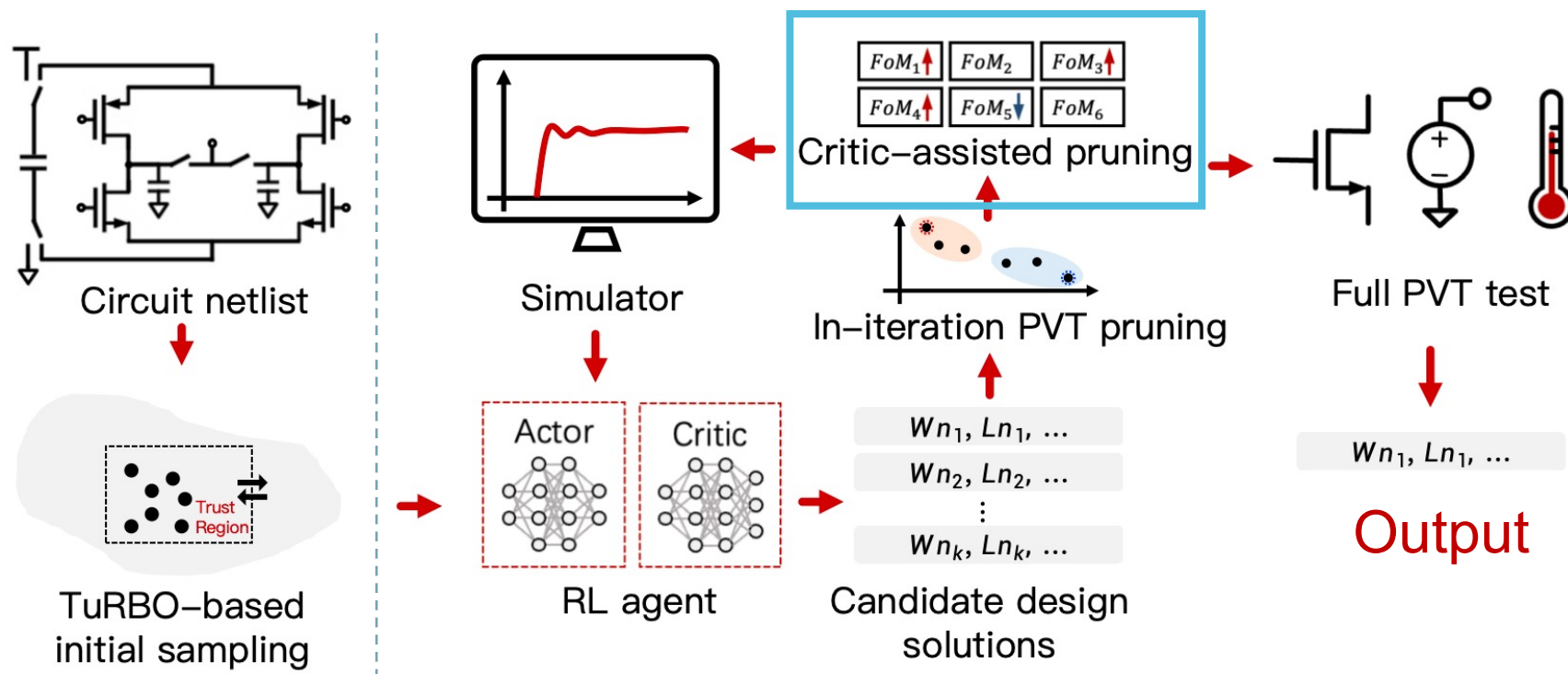
Contribution 2: In-iteration PVT pruning



w/o corner-overfitting



This work: PVTsizing



Contribution 3/3: Critic-assisted pruning for selecting candidate design solutions

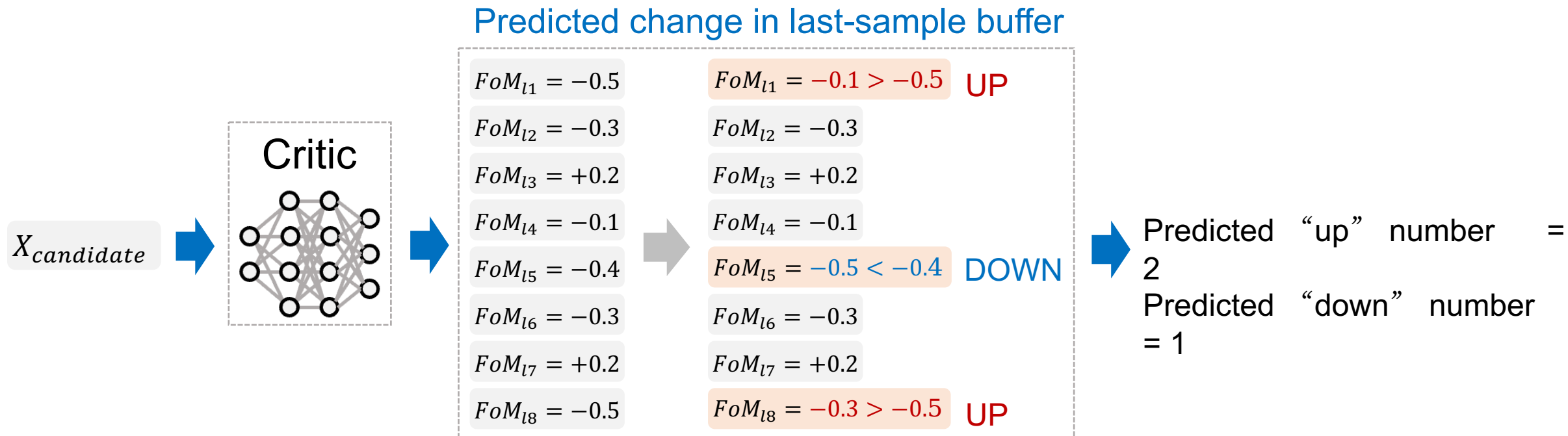
Contribution 3: Critic-assisted pruning

Reduced PVT corner set

Corner -1-

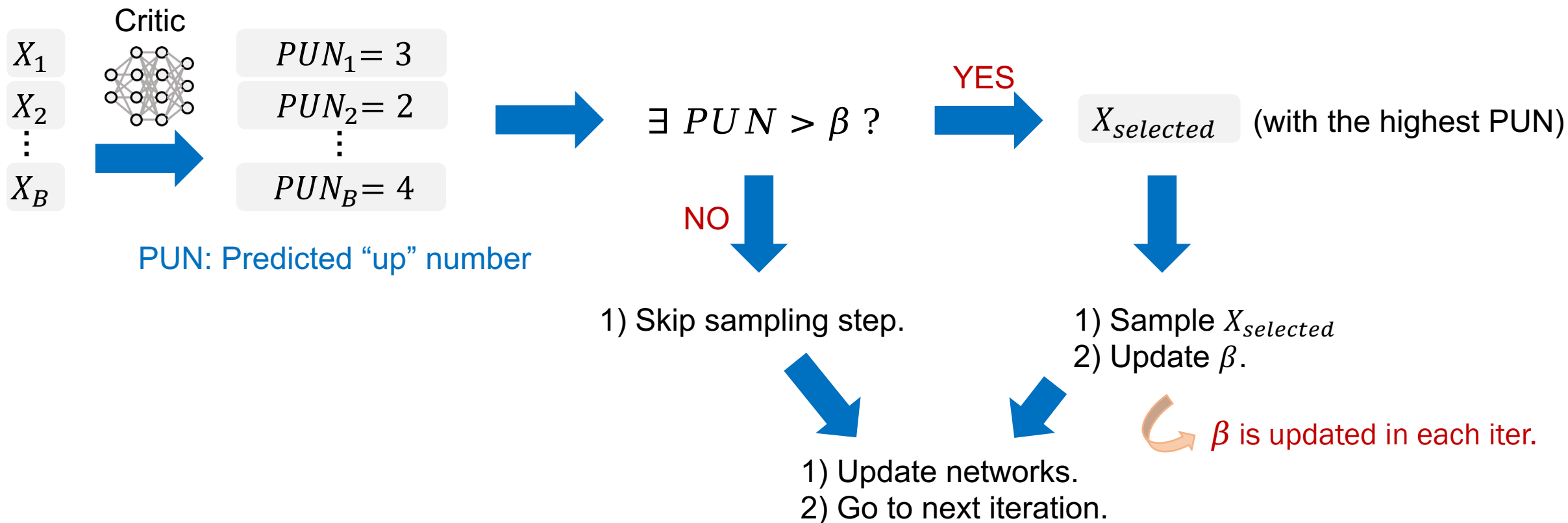
Corner -5-

Corner -8-



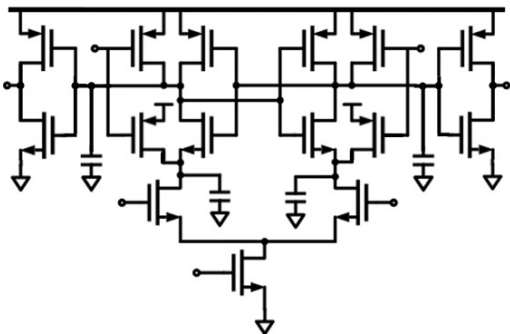
Use Critic network to predict the relative FoM of latest sample and $X_{candidate}$.

Contribution 3: Critic-assisted pruning

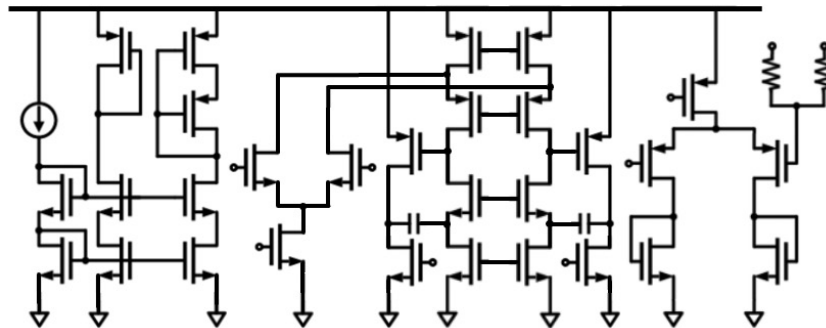


Set sample threshold β for further pruning.

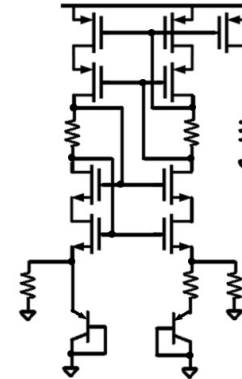
Testcases



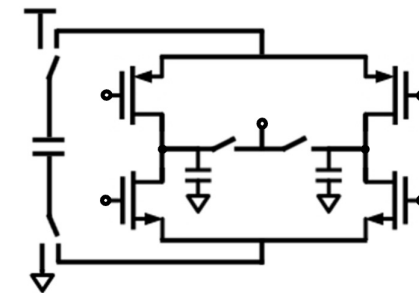
StrongArm Latch (SA)



Folded-Cascode OTA (FC)



Bandgap Reference (BGR)

Floating Inverter
Pre-Amplifier (FIA)

Topology	# of variables	# of constraints	Scale of design space
SA	14	4	10^{24}
FC	20	7	10^{55}
BGR	8	3	10^{23}
FIA	6	2	10^{17}

Synthesis results on four real-world circuits

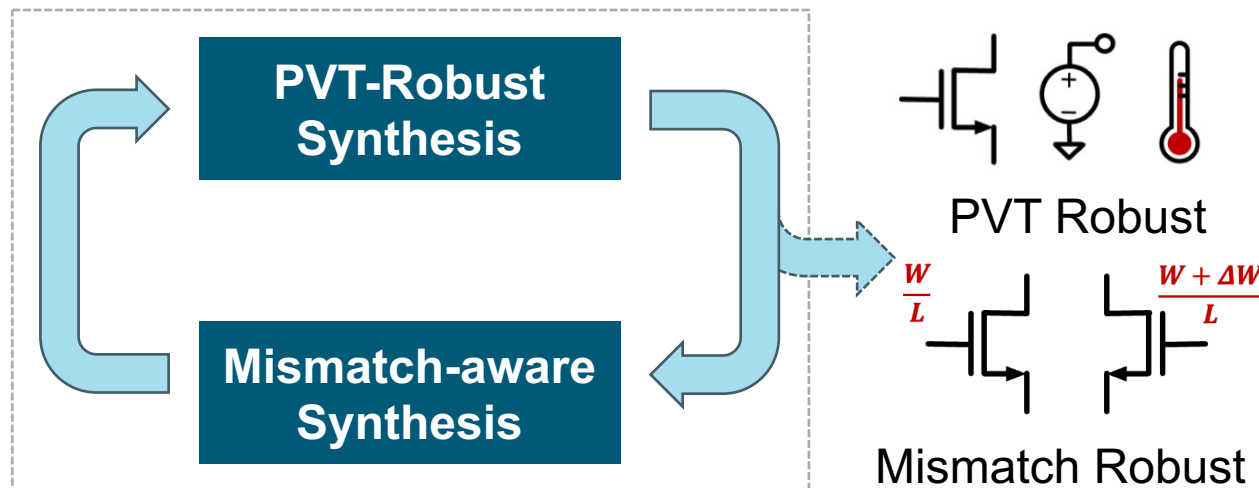
- **1.9~8.8x** sample efficiency and **1.6~9.8x** time efficiency compared to tools from industry and academia.
- Remain high success rate.

Testcases		FC OTA	StrongArm	BGR	FIA
# of samples	PVT Sizing	538	174	365	334
	Virtuoso	1023	674	3232	764
	RobustAnalog	4202	2033	8238	2043
Sample efficiency improvement		1.9×	3.8×	8.8×	2.2×
Runtime	PVT Sizing	0.68h	0.25h	0.43h	0.29h
	Virtuoso	1.14h	2.45h	1.63h	0.88h
	RobustAnalog	3.87h	3.00h	8.59h	2.93h
Time efficiency improvement		1.6×	9.8×	3.7×	3.0×
Success rate	PVT Sizing	100%	100%	90%	100%
	Virtuoso	100%	100%	100%	100%
	RobustAnalog	80%	100%	20%	100%

In tests with success rate less than 100%, only data with successful optimization are included.

Support for mismatch-aware synthesis & Results

- In Monte Carlo simulation, each simulation point corresponds to a set of mismatch parameters.
- Each set of mismatch parameters can be regarded as a mismatch corner.
- By treating mismatch corner as PVT corner, PVTsizing can handle mismatch-aware synthesis.



Results of mismatch-aware synthesis on FC OTA

Framework	# of samples	Runtime	Succeeded?
PVTsizing	823	3.73h	Yes
Virtuoso	5267	5.27h	Yes
Improvement	6.4×	1.4×	/

Conclusion

➤ PVT Sizing

- **A TuRBO-RL framework** is proposed for high-success-rate PVT robust analog synthesis.
- **In-iteration PVT corner pruning** is proposed to avoid corner-overfitting.
- **Critic-assisted pruning** is proposed to improve effectiveness of performance prediction.
- **Mismatch-aware synthesis** is supported.

➤ Results

- **1.9~8.8x** sample efficiency and **1.6~9.8x** time efficiency compared to tools from industry and academia.

Thanks for your attention.